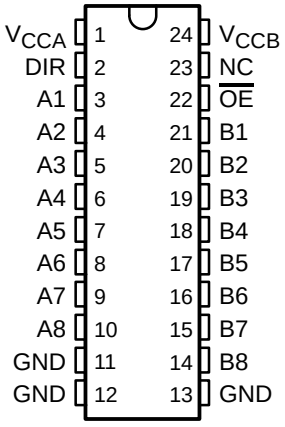
- ***EPIC***™ **(Enhanced-Performance Implanted CMOS) Submicron Process**
- **Typical V_{OLP} (Output Ground Bounce) < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C**
- **Typical V_{OHV} (Output V_{OH} Undershoot) > 2 V at V_{CC} = 3.3 V, T_A = 25°C**
- **Package Options Include Plastic Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages**

DB, DW, OR PW PACKAGE
(TOP VIEW)



description

This 8-bit (octal) noninverting bus transceiver contains two separate supply rails. The B port is designed to track V_{CCB}, which accepts voltages from 3 V to 5 V, and the A port is designed to track V_{CCA}, which is set to operate at 3.3 V. This allows for translation from a 3.3-V to a 5-V environment and vice versa.

The SN74LVCC3245 is designed for asynchronous communication between data buses. The device transmits data from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable ($\overline{OE}$) input can be used to disable the device so the buses are effectively isolated.

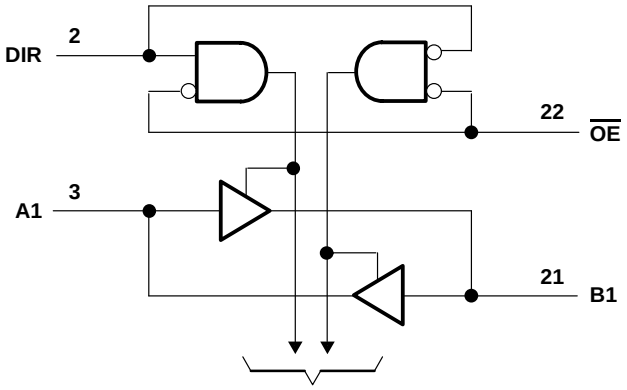
The SN74LVCC3245 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE

INPUTS		OPERATION
$\overline{OE}$	DIR	
L	L	B data to A bus
L	H	A data to B bus
H	X	Isolation

PRODUCT PREVIEW

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V_{CCA} and V_{CCB} . . . . . –0.5 V to 6 V
Input voltage range, V_I: All An (see Note 1) . . . . . –0.5 to V_{CCA} + 0.5 V
All Bn (see Note 1) . . . . . –0.5 to V_{CCB} + 0.5 V
Except I/O ports (see Note 2) . . . . . –0.5 to V_{CCA} + 0.5 V
Output voltage range, V_O (see Note 1): All An . . . . . –0.5 to V_{CCA} + 0.5 V
All Bn . . . . . –0.5 to V_{CCB} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) . . . . . –50 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$) . . . . . ±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC}) . . . . . ±50 mA
Continuous current through V_{CCA}, V_{CCB}, or GND . . . . . ±100 mA
Package thermal impedance, θ_{JA} (see Note 3): DB package . . . . . 104°C/W
DW package . . . . . 81°C/W
PW package . . . . . 120°C/W
Storage temperature range, T_{stg} . . . . . –65°C to 150°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. This value is limited to 6 V maximum.
2. This value is limited to 4.6 V maximum.
3. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 3)

				V_{CCA}	V_{CCB}	MIN	NOM	MAX	UNIT
V_{CCA}	Supply voltage					2.7	3.3	3.6	V
V_{CCB}	Supply voltage					2.7	5	5.5	V
V_{IHA}	High-level input voltage	$V_O \le 0.1$ V,	$V_O \ge V_{CCA} - 0.1$ V	2.7 V	3 V	2			V
				3 V	3.6 V	2			
				3.6 V	5.5 V	2			
V_{IHB}	High-level input voltage	$V_O \le 0.1$ V,	$V_O \ge V_{CCB} - 0.1$ V	2.7 V	3 V	2			V
				3 V	3.6 V	2			
				3.6 V	5.5 V	3.85			
V_{ILA}	Low-level input voltage	$V_O \le 0.1$ V,	$V_O \ge V_{CCA} - 0.1$ V	2.7 V	3 V			0.8	V
				3 V	3.6 V			0.8	
				3.6 V	5.5 V			0.8	
V_{ILB}	Low-level input voltage	$V_O \le 0.1$ V,	$V_O \ge V_{CCB} - 0.1$ V	2.7 V	3 V			0.8	V
				3 V	3.6 V			0.8	
				3.6 V	5.5 V			1.65	
V_{IA}	Input voltage					0		V_{CCA}	V
V_{IB}	Input voltage					0		V_{CCB}	V
V_{OA}	Output voltage					0		V_{CCA}	V
V_{OB}	Output voltage					0		V_{CCB}	V
I_{OHA}	High-level output current			2.7 V	3 V			–12	mA
				3.3 V	3 V			–24	
I_{OHB}	High-level output current			3.3 V	2.7 V			–12	mA
				3.3 V	3 V			–24	
I_{OLA}	Low-level output current			2.7 V	3 V			12	mA
				3.3 V	3 V			24	
I_{OLB}	Low-level output current			3.3 V	2.7 V			12	mA
				3.3 V	3 V			24	
$\Delta t/\Delta v$	Input transition rise or fall rate					0		10	ns/V
T_A	Operating free-air temperature					–40		85	°C

NOTE 4: Unused pins (input or I/O) must be held high or low to prevent them from floating.

PRODUCT PREVIEW

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	V_{CCA}	V_{CCB}	MIN	TYP	MAX	UNIT
V_{OHA}		I_{OH} = –100 μA	3 V	3 V	2.9	2.99		V
		I_{OH} = –12 mA	3 V	3 V	2.46	2.85		
			2.7 V	3 V	2.2	2.5		
		I_{OH} = –24 mA	3 V	3 V	2.25	2.65		
			2.7 V	4.5 V	2	2.3		
V_{OHB}		I_{OH} = –100 μA	3 V	3 V	2.9	2.99		V
		I_{OH} = –12 mA	2.7 V	3 V	2.46	2.85		
		I_{OH} = –24 mA	3 V	3 V	2.25	2.65		
			2.7 V	4.5 V	3.26	4.25		
V_{OLA}		I_{OL} = 100 μA	3 V	3 V			0.1	V
		I_{OL} = 12 mA	2.7 V	3 V		0.11	0.44	
		I_{OL} = 24 mA	3 V	3 V		0.21	0.44	
			2.7 V	4.5 V		0.22	0.5	
V_{OLB}		I_{OL} = 100 μA	3 V	3 V			0.1	V
		I_{OL} = 24 mA	3 V	3 V		0.21	0.44	
				4.5 V		0.18	0.44	
I_I	Control pins	$V_I = V_{CCA}$ or GND	3.6 V	3.6 V		±0.1	±1	μA
				5.5 V		±0.1	±1	
I_{OZ}†	A or B ports	$V_O = V_{CC}$ or GND, $V_I = V_{IL}$ or V_{IH}	3.6 V	3.6 V		±0.5	±5	μA
I_{CCA}	B to A	$A_n = V_{CC}$ or GND	3.6 V	Open		5	50	μA
		$B_n = V_{CCB}$ or GND	3.6 V	3.6 V		5	50	
				5.5 V		5	50	
I_{CCB}	A to B	$A_n = V_{CCA}$ or GND	3.6 V	3.6 V		5	50	μA
				5.5 V		8	80	
ΔI_{CCA}‡	A port	$V_I = V_{CCA}$ – 0.6 V, Other inputs at V_{CCA} or GND, $\overline{OE}$ at GND and DIR at V_{CCA}	3.6 V	3.6 V		0.35	0.5	mA
	$\overline{OE}$	$V_I = V_{CCA}$ – 0.6 V, Other inputs at V_{CCA} or GND, DIR at V_{CCA} or GND	3.6 V	3.6 V		0.35	0.5	
	DIR	$V_I = V_{CCA}$ – 0.6 V, Other inputs at V_{CCA} or GND, $\overline{OE}$ at V_{CCA} or GND	3.6 V	3.6 V		0.35	0.5	
ΔI_{CCB}‡	B port	$V_I = V_{CCB}$ – 2.1 V, Other inputs at V_{CCB} or GND, $\overline{OE}$ at GND and DIR at V_{CCB}	3.6 V	5.5 V		1	1.5	mA
C_i	Control inputs	$V_I = V_{CCA}$ or GND	Open	Open				pF
C_{io}	A or B ports	$V_O = V_{CCA}$ or GND	3.3 V	5 V				pF
C_{pd}	A to B		3.3 V	5 V				pF
	B to A							

† For I/O ports, the parameter I_{OZ} includes the input leakage current.
‡ This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CCB}.

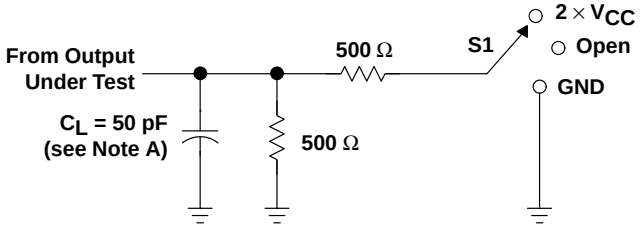
switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CCA} = 3.3 V ± 0.3 V, V_{CCB} = 5 V ± 0.5 V			V_{CCA} = 3.3 V ± 0.3 V, V_{CCB} = 3 V TO 3.6 V			UNIT
			MIN	TYP†	MAX	MIN	TYP‡	MAX	
t_{PHL}	A	B	1	4.8	8.5	1	5.5	9	ns
t_{PLH}			1	3.9	7	1	5.2	8.5	
t_{PHL}	B	A	1	3.8	7	1	4.4	7.5	ns
t_{PLH}			1	4.3	8	1	5.1	8	
t_{PZL}	$\overline{OE}$	A	1	5.9	10	1	6.4	10.5	ns
t_{PZH}			1	5.4	9.5	1	5.8	9.5	
t_{PZL}	$\overline{OE}$	B	1	4.7	8.5	1	6	9.5	ns
t_{PZH}			1	4.8	9	1	6.1	10	
t_{PLZ}	$\overline{OE}$	A	1	3.1	7	1	3.4	7	ns
t_{PHZ}			1	4.6	10	1	5.2	10	
t_{PLZ}	$\overline{OE}$	B	1	3.8	8	1	4.5	8.5	ns
t_{PHZ}			1	4	8.5	1	6.3	10	
$t_{sk(o)}$§	Data or output	Output		1	1.5		1	1.5	ns

† Typical values are at T_A = 25°C, V_{CCA} = 3.3 V, and V_{CCB} = 5 V.
‡ Typical values are at T_A = 25°C, V_{CCA} = 3.3 V, and V_{CCB} = 3.3 V.
§ Skew is the difference in the propagation delay of any two outputs of the same device. This parameter is ensured by design.

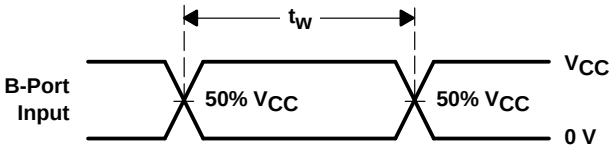
PRODUCT PREVIEW

PARAMETER MEASUREMENT INFORMATION FOR B PORT (SEE NOTE E)

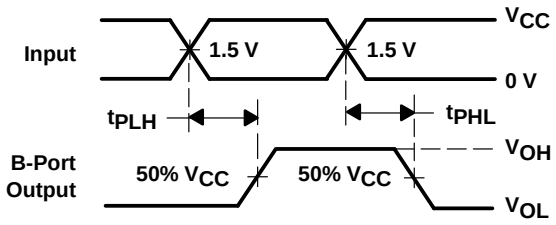


TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	2 × V_{CC}
t_{PHZ}/t_{PZH}	Open

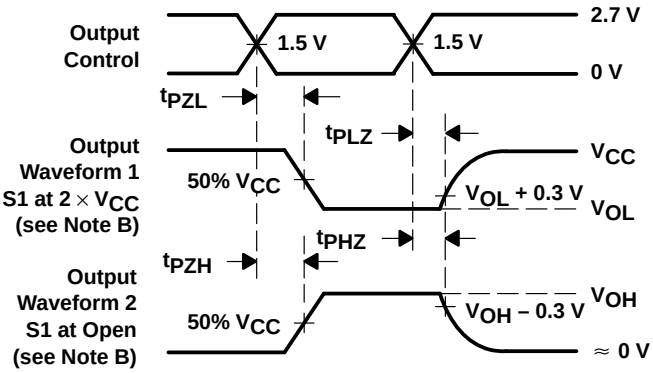
LOAD CIRCUIT



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
NONINVERTING OUTPUTS

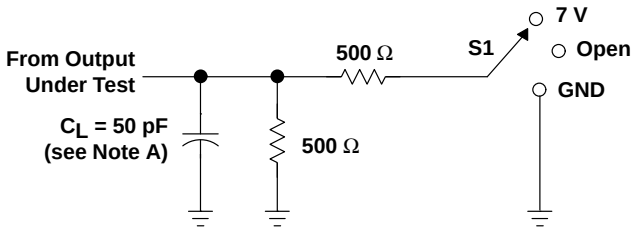


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. This is to test the B port, with V_{CCA} = 3.6 V and V_{CCB} = 5.5 V.

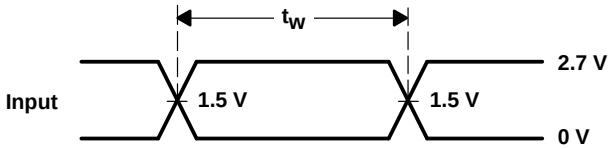
Figure 1. Load Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION FOR A AND B PORT (SEE NOTE E)

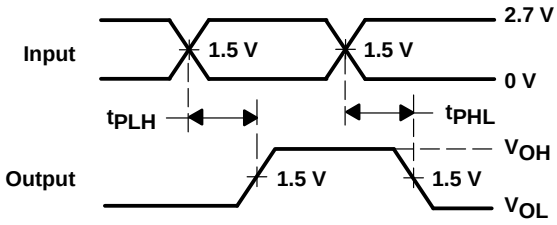


TEST	S1
t_{PLH}/t_{PHL}	Open
t_{PLZ}/t_{PZL}	7 V
t_{PHZ}/t_{PZH}	Open

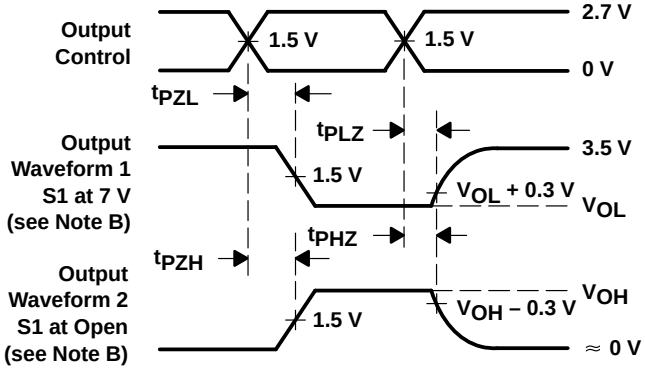
LOAD CIRCUIT



VOLTAGE WAVEFORMS
PULSE DURATION



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES
NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES
LOW- AND HIGH-LEVEL ENABLING

NOTES: A. C_L includes probe and jig capacitance.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r ≤ 2.5 ns, t_f ≤ 2.5 ns.
D. The outputs are measured one at a time with one transition per measurement.
E. This is to test the A and B ports, with V_{CCA} = 3.6 V and V_{CCB} = 3.6 V.

Figure 2. Load Circuit and Voltage Waveforms

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